

**Search Notes****Application/Control No.**

10/052,256

**Examiner**

Chau Nguyen

**Applicant(s)/Patent under Reexamination**

TERUUCHI ET AL.

**Art Unit**

2176

**SEARCHED**

Class	Subclass	Date	Examiner
715	513	8/31/2006	CN
715	514	8/31/2006	CN
715	531	8/31/2006	CN
713	176	8/31/2006	CN
713	179	8/31/2006	CN
713	180	8/31/2006	CN
713	189	8/31/2006	CN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Reports	12/15/2004	CN
	12/16/2004	CN
	12/17/2004	CN
Updated Search on East Reports	8/23/2005	CN
Updated Search on East Reports	02/07/2006	CN
	2/8/2006	CN
	02/09/2006	CN
NPL SEArch on IEEE Database	2/9/2006	CN

### **Search Notes (continued)**



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